Tamkang University Academic Year 110, 2nd Semester Course Syllabus

Course Title	INTRODUCTION OF ELECTRON MICROSCOPY	Instructor	CHIANG, CHENG-TIEN					
Course Class	TSAXB4A BACHELOR'S PROGRAM IN ADVANCED MATERIALS SCIENCE, 4A General Selection One Selection							
Relevance to SDGs	SDG4 Quality education							
	Departmental Aim of Educ	ation						
I. Enrich	the fundamental knowledge of advanced material sciences.							
П. Empha	size the ability of self-expression.							
Ⅲ. Strengt	then the ability to experiment and team spirit.							
IV. Develo	p an international perspective and international exchanges.							
	Subject Departmental core competenc	es						
A. Possess (ratio:50	a fundamental knowledge of mathematics, physics, chemistry a	nd biology.						
	e professional knowledge, experimental skills and the application stronic, biomedical and macromolecular materials.(ratio:50.00)	ns of nano,						
	Subject Schoolwide essential virtues							
5. Indeper	ndent thinking. (ratio:50.00)							
7. A spirit o	of teamwork and dedication. (ratio:50.00)							
	Introduction of electron microscopies and their applications, of optics, electron optics, and their instrumentation.	including the	basics					
Course Introduction								

The correspondences between the course's instructional objectives and the cognitive, affective, and psychomotor objectives.

Differentiate the various objective methods among the cognitive, affective and psychomotor domains of the course's instructional objectives.

I. Cognitive: Emphasis upon the study of various kinds of knowledge in the cognition of the course's veracity, conception, procedures, outcomes, etc.

II. Affective: Emphasis upon the study of various kinds of knowledge in the course's appeal, morals, attitude, conviction, values, etc.

III.Psychomotor: Emphasis upon the study of the course's physical activity and technical manipulation.

No.			objective methods				
1	Knowledge c	of electro	n microscopies	Cognitive			
	The o	correspond	lences of teaching objective	s : core competences, essential virtues, teaching n	nethods, and assessment		
No.	Core Competences		Essential Virtues	Teaching Methods	Assessment		
1	AB		57	Lecture, Discussion	Discussion(including classroom and online), Report(including oral and written), Activity Participation		
				Course Schedule			
Week	Date		Соц	urse Contents	Note		
1	111/02/21 ~ 111/02/25	overview, geometric optics, Fermat principle					
2	111/02/28 ~ 111/03/04	mirror, prism, lens					
3	111/03/07 ~ 111/03/11	vector field, gradient, curl, divergence					
4	111/03/14 ~ 111/03/18	Maxwe	Maxwell equations				
5	111/03/21 ~ 111/03/25	wave e	wave equation, Huygens-Fresnel principle				
6	111/03/28 ~ 111/04/01	paraxia	paraxial wave equation				
7	111/04/04 ~ 111/04/08	focus, p	focus, plan-apochromat objective				
8	111/04/11 ~ 111/04/15	interference, diffraction, grating					
9	111/04/18 ~ 111/04/22	optical microscope					
10	111/04/25 ~ 111/04/29	Midterm Exam Week					
11	111/05/02 ~ 111/05/06	spherical and chromatic aberrations, Abbe number					

13 111/05/36- 111/05/32- 111/05/30- 15 111/05/30- 16 111/05/30- 16 111/05/30- 17 111/05/31- Requirement Teaching facility Computer, Other (beamer and screen) Textbooks and Teaching Materials References References Physical principles of electron microscopy - an introduction to TEM, SEM, and AEM, R.F. Egerton, ISBN: 978-3-319-39877-8, https://doi.org/10.1007/978-3-319-39877-8, https://doi.org/10.1007/978-3-319-39877-8, https://doi.org/10.1007/978-3-319-39877-8, https://doi.org/10.1007/978-3-37-8501-3, https://doi.org/10.1007/978-3-387-76501-3, https://doi.org/10.1007/978-3-632-45240-0, https://doi.org/10.1007/978-3-632-45240-0, https://doi.org/10.1007/978-3-632-45240-0, https://doi.org/10.1007/978-3-632-45240-0 Surface microscopy with low energy electrons, E. Bauer, ISBN: 978-1-4939-0935-3, https://doi.org/10.1007/978-3-632-45240-0 Surface microscopy with low energy electrons, E. Bauer, ISBN: 978-1-4939-0935-3, https://doi.org/10.1007/978-3-632-45240-0 Surface microscopy with low energy electrons, E. Bauer, ISBN: 978-1-4939-0935-3, https://doi.org/10.1007/978-1-4939-0935-3 Number of Assignment(s) 1 (Filled in by assignment instructor only) ↑ Attendance: 40.0 % ↑ Mark of Usual: 20.0 % ↑ Midterm Exam: % ↑ Final Exam: % ↑ Other < oral report > :40.0 % This syllabus may be uploaded at the website of Course Syllabus Management System at http://doi.ais.blu.adu.tby/csp or through the link of Course Syllabus Management System at http://doi.ais.blu.adu.tby/csp or through the link of Course Syllabus Upload posted on the me page of TRU Office of Academic Affairs at http://www.aadatdu.tat/Cs/main.php.	12	111/05/09 ~ 111/05/13	optical microscope					
111/05/27 electrostatic lens, electron microscope	13		cathod ray, magnetic lens					
15 111/06/03 111/06/05 111/06/05 111/06/17 11	14		electrostatic lens, electron microscope					
11 11 10 10 10 10 10 10	15		Graduate Exam Week					
11 11 106/17 11 11 106/20 11 11 106/24	16							
Requirement Teaching Facility Gomputer, Other (beamer and screen)	17							
Teaching Facility Computer, Other (beamer and screen) Introduction to optics, G. Chartier, ISBN: 978-0-387-27598-7, https://doi.org/10.1007/b106780 Physical principles of electron microscopy - an introduction to TEM, SEM, and AEM, R.F. Egerton, ISBN: 978-3-319-39877-8, https://doi.org/10.1007/978-3-319-39877-8 Transmission electron microscopy - a textbook for materials science, part I. basics, D. B. Williams and C. B. Carter, ISBN: 978-0-387-76501-3, https://doi.org/10.1007/978-0-387-76501-3 Introduction to electrodynamics, D. J. Griffiths, ISBN: 978-1108420419, https://doi.org/10.1007/9781108333511 Scanning probe microscopy - atomic force microscopy and scanning tunneling microscopy, B. Voigtl8.#228,nder, ISBN: 978-3-662-45240-0, https://doi.org/10.1007/978-3-662-45240-0 Surface microscopy with low energy electrons, E. Bauer, ISBN: 978-1-4939-0935-3, https://doi.org/10.1007/978-1-4939-0935-3 Number of Assignment(s) 1 (Filled in by assignment instructor only) ↑ Attendance : 40.0 % ↑ Mark of Usual : 20.0 % ↑ Midterm Exam : % ↑ Final Exam : % ↑ Other 〈oral report〉 : 40.0 % This syllabus may be uploaded at the website of Course Syllabus Management System at http://info.ais.tku.edu.tw/csp or through the link of Course Syllabus Upload posted on the home page of TKU Office of Academic Affairs at http://www.acad.tku.edu.tw/cS/main.php.	18							
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